## XC3100A Logic Cell Array Families

Product Specifications

## Features

- Ultra-high-speed FPGA family with six members
- $50-85 \mathrm{MHz}$ system clock rates
- 190 to 325 MHz guaranteed flip-flop toggle rates
- 1.75 to 4.1 ns logic delays
- High-end additional family member in the $22 \times 22$ CLB array-size XC3195A device
- 8 mA output sink current and 8 mA source current
- Maximum power-down and quiescent current is 5 mA
- Both families are $100 \%$ architecture and pin-out compatible with other XC3000 families
- Beyond this, XC3100A is also software and bitstream compatible with the XC3000, XC3000A, and XC3000L families
- $100 \% \mathrm{PCl}$ complaint ( $\mathrm{A}-2$ speed grade in plastic quad flat pack (PQFP) packaging).

XC3100A combines the features of the XC3000A and XC3100 families.

- Additional interconnect resources for TBUFs and CE inputs
- Error checking of the configuration bitstream
- Soft startup holds all outputs slew-rate limited during initial power-up
- More advanced CMOS process


## Description

The XC3100A is a performance-optimized relative of the XC3000 and XC3000A families. While all families are footprint compatible, XC3100A familiy extends the system performance beyond 80 MHz .
The XC3100A familiy follows the XC4000 speed-grade nomenclature, indicating device performance with a number that is based on the internal logic-block delay, in ns.

The XC3100A family offers the following enhancements over the popular XC3100 family.

The XC3100A family has additional interconnect resources to drive the I-inputs of TBUFs driving horizontal Longlines. The CLB Clock Enable input can be driven from a second vertical Longline. These two additions result in more efficient and faster designs when horizontal Longlines are used for data bussing.
During configuration, the XC3100A devices check the bitstream format for stop bits in the appropriate positions. Any error terminates the configuration and pulls INIT Low.

When the configuration process is finished and the device starts up in user mode, the first activation of the outputs is automatically slew-rate limited. This feature, called Soft Startup, avoids the potential ground bounce when all outputs are turned on simultaneously. After start-up, the slew rate of the individual outputs is, as in all XC3000 families, determined by the individual configuration option.

The XC3100A family is a superset of the XC3000 families. Any bitstream used to configure an XC3000, XC3000A, XC3000L or XC3100 device, will configure the same-size XC3100A device exactly the same way.

| Device | CLBs | Array | User I/O <br> Max | Flip-Flops | Horizontal <br> Longlines | Configuration <br> Data Bits |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| XC3120A | 64 | $8 \times 8$ | 64 | 256 | 16 | 14,779 |
| XC3130A | 100 | $10 \times 10$ | 80 | 360 | 20 | 22,176 |
| XC3142A | 144 | $12 \times 12$ | 96 | 480 | 24 | 30,784 |
| XC3164A | 224 | $16 \times 14$ | 120 | 688 | 28 | 46,064 |
| XC3190A | 320 | $16 \times 20$ | 144 | 928 | 40 | 64,160 |
| XC3195A | 484 | $22 \times 22$ | 176 | 1,320 | 44 | 94,944 |

Xilinx maintains test specifications for each product as controlled documents. To insure the use of the most recently released device performance parameters, please request a copy of the current test-specification revision.

## Absolute Maximum Ratings

| Symbol | Description |  | Units |
| :--- | :--- | :---: | :---: |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage relative to GND | -0.5 to +7.0 | V |
| $\mathrm{~V}_{\text {IN }}$ | Input voltage with respect to GND | -0.5 to $\mathrm{V}_{\mathrm{CC}}+0.5$ | V |
| $\mathrm{~V}_{\mathrm{TS}}$ | Voltage applied to 3-state output | -0.5 to $\mathrm{V}_{\mathrm{CC}}+0.5$ | ${ }^{\circ} \mathrm{V}$ |
| $\mathrm{T}_{\text {STG }}$ | Storage temperature (ambient) | -65 to +150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {SOL }}$ | Maximum soldering temperature (10 s @ 1/16 in.) | +260 | ${ }^{\circ} \mathrm{C}$ |
|  | Junction temperature plastic | +125 | ${ }^{\circ} \mathrm{C}$ |
|  | Junction temperature ceramic | +150 | ${ }^{\circ} \mathrm{C}$ |

Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

## Operating Conditions

| Symbol | Description | Min | Max | Units |
| :--- | :--- | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage relative to GND Commercial $0^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ junction | 4.75 | 5.25 | V |
|  | Supply voltage relative to GND Industrial $-40^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$ junction | 4.5 | 5.5 | V |
| $\mathrm{~V}_{\text {IHT }}$ | High-level input voltage - TTL configuration | 2.0 | $\mathrm{~V}_{\mathrm{CC}}$ | V |
| $\mathrm{V}_{\text {ILT }}$ | Low-level input voltage - TTL configuration | 0 | 0.8 | V |
| $\mathrm{~V}_{\text {IHC }}$ | High-level input voltage - CMOS configuration | $70 \%$ | $100 \%$ | $\mathrm{~V}_{\mathrm{CC}}$ |
| $\mathrm{V}_{\text {ILC }}$ | Low-level input voltage - CMOS configuration | 0 | $20 \%$ | $\mathrm{~V}_{\mathrm{CC}}$ |
| $\mathrm{T}_{\text {IN }}$ | Input signal transition time |  | 250 | ns |

At junction temperatures above those listed as Operating Conditions, all delay parameters increase by $0.3 \%$ per ${ }^{\circ} \mathrm{C}$.

## DC Characteristics Over Operating Conditions

| Symbol | Description |  | Min | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{OH}}$ | High-level output voltage ( $\mathrm{l}_{\mathrm{OH}}=-8.0 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}} \mathrm{min}$ ) | Commercial | 3.86 |  | V |
| $\mathrm{V}_{\mathrm{OL}}$ | Low-level output voltage ( $@ \mathrm{l}_{\mathrm{OL}}=8.0 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}} \mathrm{min}$ ) |  |  | 0.40 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | High-level output voltage ( $\left.\mathrm{l}_{\mathrm{OH}}=-8.0 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}} \mathrm{min}\right)$ | Industrial | 3.76 |  | V |
| $\mathrm{V}_{\text {OL }}$ | Low-level output voltage ( $\mathrm{l}_{\mathrm{OL}}=8.0 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}} \mathrm{min}$ ) |  |  | 0.40 | V |
| $\mathrm{V}_{\text {CCPD }}$ | Power-down supply voltage (PWRDWN must be Low) |  | 2.30 |  | V |
| $\mathrm{I}_{\mathrm{cco}}$ | Quiescent LCA supply current Chip thresholds programmed as CMOS levels ${ }^{1}$ |  |  | 8 | mA |
|  | Chip thresholds programmed as TTL levels |  |  | 14 | mA |
| $1 / 1$ | Input Leakage Current |  | -10 | +10 | $\mu \mathrm{A}$ |
| $\mathrm{C}_{\text {IN }}$ | Input capacitance, all packages except PGA175 (sample tested) <br> All Pins except XTL1 and XTL2 <br> XTL1 and XTL2 |  |  | $\begin{aligned} & 10 \\ & 15 \end{aligned}$ | $\begin{aligned} & \mathrm{pF} \\ & \mathrm{pF} \end{aligned}$ |
|  | Input capacitance, PGA 175 (sample tested) All Pins except XTL1 and XTL2 XTL1 and XTL2 |  |  | $\begin{aligned} & 15 \\ & 20 \end{aligned}$ | $\begin{aligned} & \mathrm{pF} \\ & \mathrm{pF} \end{aligned}$ |
| $\mathrm{I}_{\text {RIN }}$ | Pad pull-up (when selected) @ $\mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ (sample tested) |  | 0.02 | 0.17 | mA |
| IRLL | Horizontal long line pull-up (when selected) @ logic Low |  | 0.20 | 2.80 | mA |

Note: 1. With no output current loads, no active input or long line pull-up resistors, all package pins at $\mathrm{V}_{\mathrm{CC}}$ or GND, and the LCA configured with a MakeBits tie option.
2. Total continuous output sink current may not exceed 100 mA per ground pin. The number of ground pins varies from two for the XC3120A in the PC84 package, to eight for the XC3195A in the PQ208 or PG223 package.

## CLB Switching Characteristic Guidelines



## Buffer (Internal) Switching Characteristic Guidelines

| Speed Grade |  | -5 | -4 | -3 | -2 | -1 | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Description | Symbol | Max | Max | Max | Max | Max |  |
| Global and Alternate Clock Distribution* <br> Either: Normal IOB input pad through clock buffer to any CLB or IOB clock input <br> Or: Fast (CMOS only) input pad through clock buffer to any CLB or IOB clock input |  |  |  |  |  | - |  |
|  | $\mathrm{T}_{\text {PID }}$ | 6.8 | 6.5 | 5.6 | 5.2 | 4.8 | ns |
|  | $\mathrm{T}_{\text {PIDC }}$ | 5.4 | 5.1 | 4.3 | 4.0 |  | ns |
| TBUF driving a Horizontal Long line (L.L.)* <br> I to L.L. while T is Low (buffer active) (XC3100) <br> (XC3100A) <br> $T \downarrow$ to $L . L$. active and valid with single pull-up resistor <br> $T \downarrow$ to $\mathrm{L} . \mathrm{L}$. active and valid with pair of pull-up resistors <br> $T \uparrow$ to L.L. High with single pull-up resistor <br> $T \uparrow$ to L.L. High with pair of pull-up resistors |  |  |  |  |  | L |  |
|  | T 10 | 4.1 | 3.7 | 3.1 |  | Z | ns |
|  | $\mathrm{T}_{10}$ | 3.6 | 3.6 | 3.1 | 3.1 | 2.9 | ns |
|  | Ton | 5.6 | 5.0 | 4.2 | 4.2 | 4.0 | ns |
|  | Ton | 7.1 | 6.5 | 5.7 | 5.7 | 5.5 | ns |
|  | Tpus | 15.6 | 13.5 | 11.4 | 11.4 | 10.4 | ns |
|  | $\mathrm{T}_{\text {PUF }}$ | 12.0 | 10.5 | 8.8 | 8.1 | 7.1 | ns |
| BIDI <br> Bidirectional buffer delay |  |  |  |  |  | $\bigcirc$ |  |
|  | $\mathrm{T}_{\text {BIII }}$ | 1.4 | 1.2 | 1.0 | 0.9 | 0.85 | ns |

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## CLB Switching Characteristic Guidelines (continued)

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100\% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the XACT timing calculator and used in the simulator.

| Speed Grade |  |  | -5 |  | -4 |  | -3 |  | -2 |  | -1 |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Description |  | mbol | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max |  |
| Combinatorial Delay Logic Variables A, B, C, D, E, to outputs X or Y | 1 | TILO |  | 4.1 |  | 3.3 |  | 2.7 |  | 2.2 |  | 1.75 | ns |
| Sequential delay <br> Clock $K$ to outputs $X$ or $Y$ <br> Clock K to outputs X or Y when Q is returned through function generators F or G to drive $X$ or $Y$ | 8 | $\begin{aligned} & \mathrm{T}_{\text {Ско }} \\ & \mathrm{T}_{\text {QLO }} \end{aligned}$ |  | $3.1$ $6.3$ |  | $\begin{aligned} & 2.5 \\ & 5.2 \end{aligned}$ |  | $2.1$ $4.3$ |  | $1.7$ $3.5$ |  | $\begin{array}{\|c} 1.4 \\ 3.2 \end{array}$ | ns <br> ns |
| Set-up time before clock K  <br> Logic Variables A, B, C, D, E <br> Data In DI <br> Enable Clock EC <br> Reset Direct inactive RD | $\begin{aligned} & 2 \\ & 4 \\ & 6 \end{aligned}$ | TICK <br> T ${ }_{\text {DICK }}$ <br> TECCK | $\begin{array}{\|l} 3.1 \\ 2.0 \\ 3.8 \\ 1.0 \end{array}$ |  | $\begin{aligned} & 2.5 \\ & 1.6 \\ & 3.2 \\ & 1.0 \end{aligned}$ |  | $\begin{array}{\|l} 2.1 \\ 1.4 \\ 2.7 \\ 1.0 \end{array}$ |  | $\begin{aligned} & 1.8 \\ & 1.3 \\ & 2.5 \\ & 1.0 \end{aligned}$ |  | 1.7 1.2 2.3 1.0 | $\rightleftharpoons$ | ns ns ns ns |
| Hold Time after clock k  <br> Logic Variables A, B, C, D, E <br> Data In DI <br> Enable Clock EC | $\begin{aligned} & 3 \\ & 5 \\ & 7 \end{aligned}$ | $\mathrm{T}_{\mathrm{CKI}}$ <br> TCkDI <br> $\mathrm{T}_{\text {CKEC }}$ | $\begin{array}{\|c} 0 \\ 1.0 \\ 1.0 \end{array}$ |  | $\begin{array}{r} 0 \\ 1.0 \\ 0.8 \end{array}$ |  | $\begin{array}{\|c} 0 \\ 0.9 \\ 0.7 \end{array}$ |  | $\begin{gathered} 0 \\ 0.9 \\ 0.7 \end{gathered}$ |  | 0.8 0.6 |  | $\begin{aligned} & \mathrm{ns} \\ & \text { ns } \\ & \text { ns } \end{aligned}$ |
| Clock <br> Clock High time Clock Low time Max. flip-flop toggle rate | $\begin{aligned} & 11 \\ & 12 \end{aligned}$ | $\mathrm{T}_{\mathrm{CH}}$ <br> $\mathrm{T}_{\mathrm{CL}}$ <br> $\mathrm{F}_{\text {CLK }}$ | $\begin{aligned} & 2.4 \\ & 2.4 \\ & 190 \end{aligned}$ |  | $\begin{array}{\|l} 2.0 \\ 2.0 \\ 230 \end{array}$ |  | $\begin{array}{\|l\|l} 1.6 \\ 1.6 \\ 270 \end{array}$ |  | $\begin{aligned} & 1.3 \\ & 1.3 \\ & 322 \end{aligned}$ |  | 1.3 325 |  | $\begin{gathered} \mathrm{ns} \\ \mathrm{~ns} \\ \mathrm{MHz} \end{gathered}$ |
| Reset Direct (RD) RD width delay from RD to outputs X or Y | $\begin{array}{\|c} 13 \\ 9 \end{array}$ | TRPW $\mathrm{T}_{\text {RIO }}$ | 3.8 | 4.4 | 3.2 | 3.7 | 2.7 | 3.1 | 2.3 | 2.7 |  | $2.4$ | ns |
| Global Reset, from RESET Pad, <br> RESET width (Low) <br> (XC3142A) <br> delay from RESET pad to outputs $X$ or $Y$ |  | $\begin{aligned} & \mathrm{T}_{\mathrm{MRW}} \\ & \mathrm{~T}_{\mathrm{MRQ}} \end{aligned}$ | 14.0 | 17.0 | 14.0 | 14.0 | 12.0 | 12.0 | 12.0 | 12.0 | 12.0 | $12.0$ | ns ns |

Notes: The CLB K to Q output delay ( $\mathrm{T}_{\mathrm{CKO}}, \# 8$ ) of any CLB, plus the shortest possible interconnect delay, is always longer than the Data $\ln$ hold time requirement ( $\mathrm{T}_{\text {CKDI }}, \# 5$ ) of any CLB on the same die.
$\mathrm{T}_{\text {ILO }}, \mathrm{T}_{\text {QLO }}$ and $\mathrm{T}_{\text {ICK }}$ are specified for 4-input functions. For 5 -input functions or base FGM functions, each of these specifications for the XC3100A family increses by $0.50 \mathrm{~ns}(-5), 0.42 \mathrm{~ns}(-4)$ and $0.35 \mathrm{~ns}(-3)$.

## IOB Switching Characteristic Guidelines



## IOB Switching Characteristic Guidelines (continued)

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100\% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the XACT timing calculator and used in the simulator.


Notes: 1. Timing is measured at pin threshold, with 50 pF external capacitive loads (incl. test fixture). For larger capacitive loads, see XAPP 024. Typical slew rate limited output rise/fall times are approximately four times longer.
2. Voltage levels of unused (bonded and unbonded) pads must be valid logic levels. Each can be configured with the internal pull-up resistor or alternatively configured as a driven output or driven from an external source.
3. Input pad set-up time is specified with respect to the internal clock (IK). In order to calculate system set-up time, subtract clock delay (pad to ik) from the input pad set-up time value. Input pad holdtime with respect to the internal clock (IK) is negative. This means that pad level changes immediately before the internal clock edge (IK) will not be recognized.
4. $T_{\text {PID }}, T_{\text {PTG }}$, and $T_{\text {PICK }}$ are 3 ns higher for XTAL2 when the pin is configured as a user input.

For a detailed description of the device architecture, see pages 2-105 through 2-123.
For a detailed description of the configuration modes and their timing, see pages 2-124 through 2-132.
For detailed lists of package pin-outs, see pages 2-140 through 2-150.
For package physical dimensions and thermal data, see Section 4.


## Component Availability




[^0]:    * Timing is based on the XC3142A, for other devices see XACT timing calculator.

